Gallium Nitride 28V 50W, RF Power Transistor

Description

The NU4005H is a 50W , GaN HEMT, designed for multiple applications with frequencies up to 4GHz.

There is no guarantee of performance when this part is used in applications designed Outside of these frequencies.

 \bullet Typical performance (on Innogration narrow band fixture with device soldered) V_{DD} =28V I_{DQ} =300mA, CW.

Frequency(MHz)	Gp (dB)	P _{1dB} (W)	Efficiency (%)
1300	19	50	70

NU4005H

Applications and Features

- Suitable for wireless communication infrastructure, wideband amplifier, EMC testing, ISM etc.
- High Efficiency and Linear Gain Operations
- Thermally Enhanced Industry Standard Package
- High Reliability Metallization Process
- Excellent thermal Stability and Excellent Ruggedness
- Compliant to Restriction of Hazardous Substances (RoHS)
 Directive 2002/95/EC

Important Note: Proper Biasing Sequence for GaN HEMT Transistors

Turning the device ON

- 1. Set VGS to the pinch--off (VP) voltage, typically -5 V
- 2. Turn on VDS to nominal supply voltage (28V)
- 3. Increase VGS until IDS current is attained
- 4. Apply RF input power to desired level

Turning the device OFF

- 1. Turn RF power off
- 2. Reduce VGS down to VP, typically -5 V
- 3. Reduce VDS down to 0 V
- 4. Turn off VGS

Table 1. Maximum Ratings (Not simultaneous, TC = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
DrainSource Voltage	$V_{ t DSS}$	150	Vdc
GateSource Voltage	$V_{\sf GS}$	-10,+2	Vdc
Operating Voltage	V_{DD}	40	Vdc
Maximum Forward Gate Current	Igmax	14	mA
Storage Temperature Range	Tstg	-65 to +150	°C
Case Operating Temperature	T _c	+150	°C
Operating Junction Temperature(See note 1)	T٦	+200	°C
Total Device Power Dissipation (Derated above 25°C, see note 2)	Pdiss	60	W

- 1. Continuous operation at maximum junction temperature will affect MTTF
- 2. Bias Conditions should also satisfy the following expression: Pdiss < (Tj Tc) / RJC and Tc = Tcase

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Table 2. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case	Rejc-dc	3.2	C/W
T _C = 85°C, T _J =200°C, DC Power Dissipation(See note 1)	NθJC-DC	5.2	

^{1.} ReJC-DC is tested at only DC condition, it is related to the highest thermal resistor value among all test conditions. It might be differently lower in different RF operation conditions like CW signal ,pulsed RF signal etc.

Table 3. Electrical Characteristics (T_C = 25 °C unless otherwise noted)

DC Characteristics

Characteristic	Conditions	Symbol	Min	Тур	Max	Unit
Drain-Source Breakdown Voltage	V _{GS} =-8V; I _{DS} =14mA	V_{DSS}	150			V
Gate Threshold Voltage	V _{DS} = 28V, I _D = 14mA	V _{GS} (th)		-2.7		V
Gate Quiescent Voltage	V _{DS} =28V, I _{DS} =300mA, Measured in Functional Test	V _{GS(Q)}		-2.4		V

Functional Tests (In Innogration broadband Test Fixture, 50 ohm system) :V_{DD} = 28 Vdc, I_{DQ} = 300 mA, f = 1300 MHz, CW

Characteristic	Symbol	Min	Тур	Max	Unit
Power Gain@ P _{1dB}	Gp		19		dB
Drain Efficiency @ P _{1dB}	Eff	65	70		%
1dB compressed power	P _{SAT}	45	50		W
Input Return Loss	IRL		-7		dB
Mismatch stress at all phases (Device no damage)	VSWR		10:1		Ψ

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Package Outline

Flanged ceramic package; 2 leads

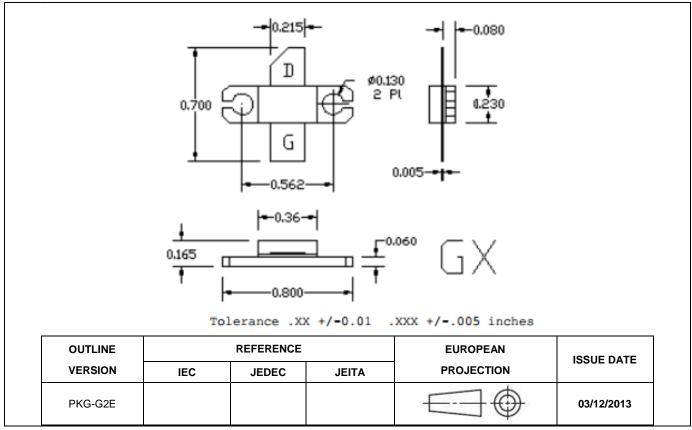


Figure 1. Package Outline PKG-G2E

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Revision history

Table 4. Document revision history

Date	Revision	Datasheet Status
2017/3/10	V1.0	Objective Datasheet Creation
2017/6/19	V1.0	Preliminary Datasheet Creation

Notice

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